SCBS097D – FEBRUARY 1991 – REVISED JANUARY 1997

<ul> <li>Members of the Texas Instruments Widebus™ Family</li> </ul>	SN54ABT16833 WD PACKAGE SN74ABT16833 DGG OR DL PACKAGE (TOP VIEW)
<ul> <li>State-of-the-Art EPIC-IIB<sup>™</sup> BiCMOS Design Significantly Reduces Power Dissipation</li> </ul>	
	10EB [1 56] 10EA
<ul> <li>Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17</li> </ul>	
	$1\overline{\text{ERR}}$ $\begin{bmatrix} 3 & 54 \end{bmatrix}$ 1PARITY
• Typical V <sub>OLP</sub> (Output Ground Bounce)	GND [] 4 53 ]] GND
< 1 V at V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C	
<ul> <li>Distributed V<sub>CC</sub> and GND Pin Configuration</li> </ul>	
Minimizes High-Speed Switching Noise	V <sub>CC</sub> [] 7 50 [] V <sub>CC</sub> 1A3 [] 8 49 [] 1B3
<ul> <li>Flow-Through Architecture Optimizes</li> </ul>	1A3 [] 8 49 ] 1B3 1A4 [] 9 48 [] 1B4
PCB Layout	1A4 [] 9 48 [] 1B4 1A5 [] 10 47 [] 1B5
<ul> <li>High-Drive Outputs (–32-mA I<sub>OH</sub>, 64-mA I<sub>OL</sub>)</li> </ul>	GND [] 11 46 ] GND
Parity-Error Flag With Parity	1A6 12 45 1B6
Generator/Checker	1A7 [] 13 44 [] 1B7
<ul> <li>Register for Storage of Parity-Error Flag</li> </ul>	1A8 [] 14 43 [] 1B8
<ul> <li>Package Options Include Plastic 300-mil</li> </ul>	2A1 15 42 2B1
Shrink Small-Outline (DL) and Thin Shrink	2A2 1 16 41 2B2
Small-Outline (DGG) Packages and 380-mil	2A3 🛛 17 40 🗍 2B3
Fine-Pitch Ceramic Flat (WD) Package	GND 🛛 18 39 🗍 GND
Using 25-mil Center-to-Center Spacings	2A4 🛛 19 🛛 38 🗍 2B4
	2A5 🛛 20 37 🗍 2B5
description	2A6 <b>[</b> 21 36 <b>]</b> 2B6
	V <sub>CC</sub> [ 22 35 ] V <sub>CC</sub>
The 'ABT16833 consist of two noninverting 8-bit	2A7 <b>[</b> 23 34 <b>]</b> 2B7
to 9-bit parity bus transceivers and are designed	2A8 <b>[</b> 24 33 <b>]</b> 2B8
for communication between data buses. For each transceiver, when data is transmitted from the	GND [] 25 32 ]] GND
A bus to the B bus, an odd-parity bit is generated	2ERR 26 31 2PARITY
and output on the parity I/O pin (1PARITY or	2 <u>CLK</u> 27 30 2 <u>CLR</u>
2PARITY). When data is transmitted from the	20EB [28 29] 20EA

The error (1ERR or 2ERR) output is configured as an open-collector output. The B-to-A parity-error flag is clocked into 1ERR (or 2ERR) on the low-to-high transition of the clock (1CLK or 2CLK) input. 1ERR (or 2ERR) is cleared (set high) by taking the clear (1CLR or 2CLR) input low.

The output-enable ( $\overline{OEA}$  and  $\overline{OEB}$ ) inputs can be used to disable the device so that the buses are effectively isolated. When both  $\overline{OEA}$  and  $\overline{OEB}$  are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to V<sub>CC</sub> through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Widebus and EPIC-IIB are trademarks of Texas Instruments Incorporated.

2PARITY). When data is transmitted from the B bus to the A bus, 1PARITY (or 2PARITY) is configured as an input and combined with the B-input data to generate an active-low error flag if

UNLESS OTHERWISE NOTED this document contains PRODUCTION DATA information current as of publication date. Products conform to specifications per the terms of Texas instruments standard warranty. Production processing does not necessarily include testing of all parameters.

odd parity is not detected.



Copyright © 1997, Texas Instruments Incorporated

SCBS097D – FEBRUARY 1991 – REVISED JANUARY 1997

#### description (continued)

The SN54ABT16833 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74ABT16833 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

					FUNC	TION TA	BLE			
		I	NPUTS				OUTPL	JT AND I/O		
OEB	OEA	CLR	CLK	<b>Α</b> ί Σ <b>ΟF Η</b>	<b>Βi</b> † Σ <b>OF H</b>	А	В	PARITY	ERR‡	FUNCTION
L	н	х	х	Odd Even	NA	NA	А	L H	NA	A data to B bus and generate parity
н	L	Н	Ť	NA	Odd Even	в	NA	NA	H L	B data to A bus and check parity
Х	Х	L	Х	Х	Х	Х	NA	NA	Н	Check error-flag register
н	н	H L H H	No↑ No↑ ↑ ↑	X X Odd Even	х	z	Z	Z	NC H H L	Isolation§
L	L	Х	Х	Odd Even	NA	NA	А	H	NA	A data to B bus and generate inverted parity

NA = not applicable, NC = no change, X = don't care

<sup>†</sup> Summation of high-level inputs includes PARITY along with Bi inputs.

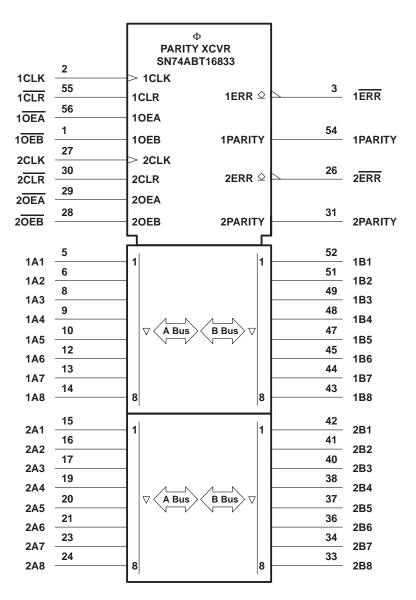
<sup>‡</sup>Output states shown assume ERR was previously high.

 $\$  In this mode,  $\overline{\text{ERR}}$  (when clocked) shows inverted parity of the A bus.



SCBS097D - FEBRUARY 1991 - REVISED JANUARY 1997

logic symbol<sup>†</sup>

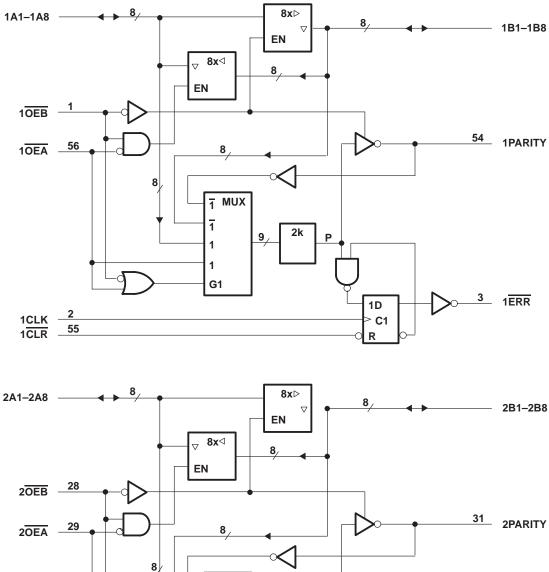


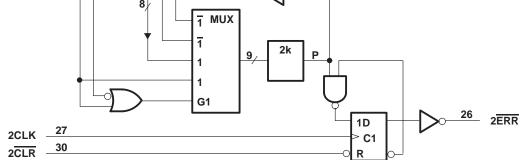
<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



SCBS097D – FEBRUARY 1991 – REVISED JANUARY 1997

### logic diagram (positive logic)





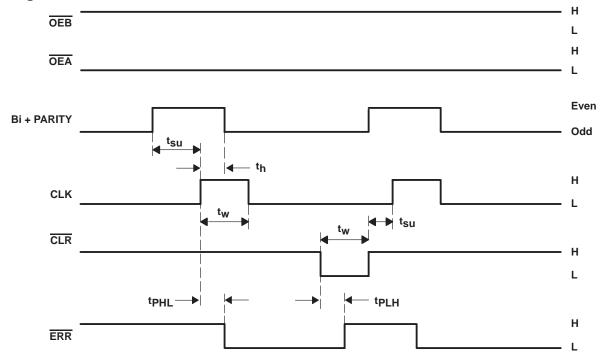


SCBS097D - FEBRUARY 1991 - REVISED JANUARY 1997

ERROR-FLAG FUNCTION TABLE											
INP	UTS	INTERNAL TO DEVICE	OUTPUT PRE-STATE	OUTPUT ERR	FUNCTION						
CLR	CLK	POINT P	EKK								
Н	$\uparrow$	Н	Н	Н							
Н	$\uparrow$	х	L	L	Sample						
Н	$\uparrow$	L	Х	L							
L	Х	Х	Х	Н	Clear						

<sup>†</sup> State of ERR before changes at CLR, CLK, or point P

## error-flag waveforms





SCBS097D - FEBRUARY 1991 - REVISED JANUARY 1997

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

### recommended operating conditions (see Note 3)

			SN54ABT	16833	SN74AB1	Г16833	UNIT
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2	h	2		V
VIL	Low-level input voltage			0.8		0.8	V
VI	Input voltage		0	Vcc	0	VCC	V
VOH	High-level output voltage	ERR	7	5.5		5.5	V
IOH	High-level output current	Except ERR	200	-24		-32	mA
IOL	Low-level output current		201	48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	Outputs enabled	4	10		10	ns/V
Т <sub>А</sub>	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.



SCBS097D - FEBRUARY 1991 - REVISED JANUARY 1997

	DAMETED	TEST CON	DITIONS	Т	A = 25°C	;	SN54AB	Г16833	SN74AB1	16833	UNIT
PA	RAMETER	TEST CON	IDITIONS	MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT
VIK		V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2		-1.2		-1.2	V
		V <sub>CC</sub> = 4.5 V,	I <sub>OH</sub> = -3 mA	2.5	3		2.5				
Vari	All outputs	V <sub>CC</sub> = 5 V,	$I_{OH} = -3 \text{ mA}$	3	3.4		3		3		v
VOH	except ERR	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -24 mA				2				v
		VCC = 4.5 V	I <sub>OH</sub> = -32 mA	2*	2.7				2		
Vei	V <sub>OL</sub> V <sub>CC</sub> = 4.		I <sub>OL</sub> = 24 mA		0.25	0.55		0.55			V
VOL		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 64 mA		0.3	0.55*				0.55	v
V <sub>hys</sub>					100			2			mV
IOH	ERR	V <sub>CC</sub> = 4.5 V,	V <sub>OH</sub> = 5.5 V			20		20		20	μA
loff		$V_{CC} = 0,$	VI or VO $\leq 4.5$ V			±100		<sup>2</sup> El		±100	μA
ICEX	Outputs high	V <sub>CC</sub> = 5.5 V,	$V_{O} = 5.5 V$			50		50		50	μA
1.	Control inputs	V <sub>CC</sub> = 5.5 V, V <sub>I</sub> = V			±1	20	±1		±1	μA	
łı	A or B ports	VCC = 5.5  v,  v =  v	CC OL GIND			±100	20	±100		±100	μι
١ <sub>IL</sub>	A or B ports	$V_{CC} = 0,$	VI = GND			-50	4d	-50		-50	μA
10‡		V <sub>CC</sub> = 5.5 V,	$V_{O} = 2.5 V$	-50	-100	-180	-50	-180	-50	-180	mA
IOZH§		V <sub>CC</sub> =5.5 V,	$V_{O} = 2.7 V$			50		50		50	μA
Iozl§		V <sub>CC</sub> = 5.5 V,	$V_{O} = 0.5 V$			-50		-50		-50	μA
		V <sub>CC</sub> = 5.5 V,	Outputs high		1.5	2		2		2	
ICC	A or B ports	IO = 0,	Outputs low		28	36		36		36	mA
		$V_{I} = V_{CC}$ or GND	Outputs disabled		1	2		2		2	
$\Delta I_{\rm CC} \P$		$V_{CC}$ = 5.5 V, One in Other inputs at $V_{CC}$				50		50		50	μΑ
Ci	Control inputs	V <sub>I</sub> = 2.5 V or 0.5 V		3						pF	
Cio	A or B ports	V <sub>O</sub> = 2.5 V or 0.5 V			9						pF

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

\* On products compliant to MIL-PRF-38535, this parameter does not apply.

<sup>†</sup> All typical values are at  $V_{CC} = 5$  V.

<sup>‡</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 $\ensuremath{\S}$  The parameters  $I_{OZH}$  and  $I_{OZL}$  include the input leakage current.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V<sub>CC</sub> or GND.



SCBS097D – FEBRUARY 1991 – REVISED JANUARY 1997

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

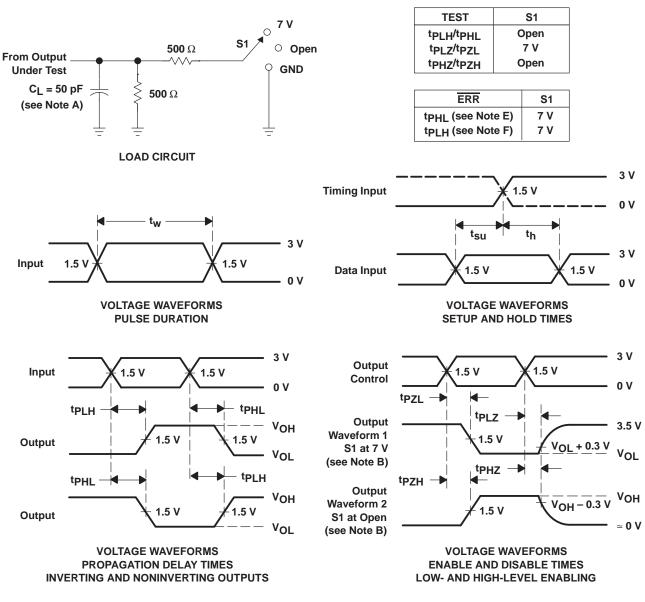
			V <sub>CC</sub> = T <sub>A</sub> = 2	⊧ 5 V, 25°C	SN54AB	Г16833	SN74AB1	Г16833	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
tw	Pulse duration, CLK high or low		3		3		3		ns
		A port	4.5		4.5	2	4.5		
t <sub>su</sub>	Setup time before CLK↑	CLR	1		81 S	4	1		ns
		OEA	5		5		5		
t <sub>h</sub>	Hold time after $CLK^\uparrow$	A port or OEA	0		0		0		ns

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>(</sub> Tj	CC = 5 V A = 25°C	/, ;	SN54AB	Г16833	SN74AB1	16833	UNIT	
		(001-01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX		
<sup>t</sup> PLH	A or B	B or A	1.5	2.5	3.3	1.5	4.2	1.5	4.1	ns	
<sup>t</sup> PHL	AUD	BUIA	2	3.1	3.9	2	4.5	2	4.3	115	
<sup>t</sup> PZH	OE	A or B	2	3.9	4.9	2	5.8	2	5.6	ns	
<sup>t</sup> PZL	OE	AUB	2.5	4.3	5.1	2.5	6.2	2.5	6	115	
<sup>t</sup> PHZ	OE	A or B	2	3.6	4.5	2	5.5	2	5.4	ns	
<sup>t</sup> PLZ	OE	AUB	1.5	3	3.8	1.5	4.7	1.5	4.3	115	
<sup>t</sup> PLH	A or OE	PARITY	2	4.6	5.4	2	7	2	6.7	ns	
<sup>t</sup> PHL	A or OE	PARITY	2	4.3	5.1	20	6.5	2	6.1	115	
<sup>t</sup> PZH	OE	PARITY	2	3.6	5	02	5.8	2	5.7	ns	
<sup>t</sup> PZL	OE		2.5	4.4	5.8	<b>2</b> .5	6.7	2.5	6.5	115	
<sup>t</sup> PHZ		PARITY	1.5	3.2	4	1.5	4.8	1.5	4.7	20	
<sup>t</sup> PLZ	OE		1.5	2.9	3.7	1.5	4.2	1.5	4.1	ns	
<sup>t</sup> PLH	CLK, CLR	<u> </u>	2	3.4	4.2	2	4.8	2	4.6	ne	
<sup>t</sup> PHL	CLK	ERR	2	2.8	3.6	2	4.1	2	3.9	ns	



SCBS097D - FEBRUARY 1991 - REVISED JANUARY 1997



### PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>f</sub>  $\leq$  2.5 ns, t<sub>f</sub>  $\leq$  2.5 ns.

D. The outputs are measured one at a time with one transition per measurement.

E. t<sub>PHL</sub> is measured at 1.5 V.

F. tpLH is measured at VOL + 0.3 V.

Figure 1. Load Circuit and Voltage Waveforms





### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74ABT16833DL	ACTIVE	SSOP	DL	56	20	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ABT16833	Samples
SN74ABT16833DLR	ACTIVE	SSOP	DL	56	1000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ABT16833	Samples
SN74ABT16833DLRG4	ACTIVE	SSOP	DL	56	1000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ABT16833	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:**The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.



www.ti.com

# PACKAGE OPTION ADDENDUM

10-Dec-2020

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# PACKAGE MATERIALS INFORMATION

www.ti.com

### TAPE AND REEL INFORMATION

#### REEL DIMENSIONS

TEXAS INSTRUMENTS





#### TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

 TAPE AND REEL INFORMATION

 \*All dimensions are nominal

Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74ABT16833DLR	SSOP	DL	56	1000	330.0	32.4	11.35	18.67	3.1	16.0	32.0	Q1

TEXAS INSTRUMENTS

www.ti.com

# PACKAGE MATERIALS INFORMATION

14-Jul-2012



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74ABT16833DLR	SSOP	DL	56	1000	367.0	367.0	55.0

### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (https://www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2021, Texas Instruments Incorporated